

EL979955253

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Priority Application Serial No. 10/232,295
Priority Filing Date August 30, 2002
Inventor Warren M. Farnworth et al.
Assignee Micron Technology, Inc.
Priority Group Art Unit 2829
Priority Examiner R. Kobert
Attorney's Docket No. MI22-2525
Title: Method and Apparatus for Testing Semiconductor Circuitry for Operability and
Method of Forming Apparatus for Testing Semiconductor Circuitry for Operability

INFORMATION DISCLOSURE STATEMENT

References - - See attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

The listed references were cited by, or submitted to, the Office in the parent, co-pending application of the above-identified application. The above-identified application is a divisional application of co-pending Application Serial No. 10/232,295, filed August 30, 2002, upon which the above-identified application relies for a priority date under 35 U.S.C. §120. Such prior disclosure is sufficient for the above-identified application as far as copies of the references are concerned. 37 C.F.R. §1.98(d) and MPEP §609(2). As a courtesy, copies of the foreign references and the articles are enclosed.

Citation of these references is respectfully requested.

Respectfully submitted,

Date: 3-17-04



D. Brent Kenady
Reg. No. 40,045
Customer No. 021567

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2525	SERIAL NO. Filed Herewith		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Warren M. Farnworth et al.			
				FILING DATE Filed Herewith	GROUP N/A		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	3,412,456	11/68	Ebisawa			
	AB	3,469,019	9/69	Reinmann			
	AC	4,105,970	8/78	Katz			
	AD	4,141,055	2/79	Berry et al.			
	AE	4,182,781	1/80	Hooper et al.			
	AF	4,189,825	2/80	Robillard et al.			
	AG	4,312,117	1/82	Robillard et al.			
	AH	4,315,984	2/82	Okazaki et al.			
	AI	4,417,206	11/83	Stowers			
	AJ	4,499,656	2/85	Fabian et al.			
	AK	4,585,991	4/86	Reid et al.			
	AL	4,881,118	11/89	Niwayama et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AM	53171	03/91	Japan			
	AN	108350	05/91	Japan			
	AO	329314	08/89	European (EPO)			
	AP	5714838	09/82	Japan			
	AQ	2-5540	01/90	Japan			
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR		Moto's Nakano "A Probe for Testing Semiconductor Integrated Circuits and a Test Method Using Said Probe." 25 March, 1991				
			Japanese Patent Office Disclosure No. Hei 3-69131, Filing No. Hei 1-205301, Filing Date August 8, 1989				
	AS						
	AT						
EXAMINER				DATE CONSIDERED			
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U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AU	4,924,589	5/90	Leedy			
	AV	4,929,999	5/90	Hoebrechts et al.			
	AW	4,937,653	6/90	Blonder et al.			
	AX	4,952,272	8/90	Okino et al.			
	AY	4,963,225	10/90	Lehman-Lemar			
	AZ	5,420,520	5/95	Anschel et al.			
	BA	5,014,161	5/91	Lee et al.			
	BB	5,032,541	7/91	Sakamoto et al.			
	BC	5,045,780	9/91	Swart			
	BD	5,072,116	12/91	Kawade et al.			
	BE	5,103,557	4/92	Leedy			
	BF	5,137,461	8/92	Bindra et al.			

FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	BG	2232946	09/90	Japan				
	BH	410446	01/92	Japan				
	BI							
	BJ							
	BK							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
	BL		
	BM		
	BN		

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	BO	5,177,438	1/93	Littlebury et al.			
	BP	5,177,439	1/93	Liu et al.			
	BQ	5,196,251	3/93	Bakhru et al.			
	BR	5,206,585	4/93	Chang et al.			
	BS	5,235,140	8/93	Reele et al.			
	BT	5,239,260	8/93	Widder et al.			
	BU	5,245,135	9/93	Schreiber et al.			
	BV	5,262,718	11/93	Svendsen et al.			
	BW	5,307,561	5/94	Feigenbaum et al.			
	BX	5,323,035	6/97	Leedy			
	BY	5,326,428	7/94	Farnworth et al.			
	BZ	5,334,804	8/94	Love et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	CA						
	CB						
	CC						
	CD						
	CE						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	CF						
	CG						
	CH						
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	CI	5,353,195	10/94	Fillion et al.			
	CJ	5,367,253	11/94	Wood et al.			
	CK	5,402,077	03/95	Agahdel et al.			
	CL	5,419,807	05/95	Akram et al.			
	CM	5,431,328	07/95	Chang et al.			
	CN	5,478,779	12/95	Akram			
	CO	5,468,917	11/95	Brodsky et al.			
	CP	5,471,151	11/95	DiFrancesco			
	CQ	5,477,087	12/95	Kwakita et al.			
	CR	5,523,697	06/96	Farnworth et al.			
	CS	5,541,525	07/96	Wood et al.			
	CT	5,559,444	09/93	Farnworth et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	CU						
	CV						
	CW						
	CX						
	CY						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	CZ						
	DA						
	DB						
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	DC	5,625,297	04/97	Amaudov et al.			
	DD	5,716,218	02/98	Farnworth et al.			
	DE	5,790,337	08/98	Schreiber et al.			
	DF	5,831,832	11/98	Gillette et al.			
	DG	5,849,633	12/98	Akram			
	DH	5,869,787	02/99	Akram			
	DI	6,002,266	12/99	Briggs et al.			
	DJ	6,093,643	07/00	Akram			
	DK	4,566,184	01/86	Higgins et al.			
	DL	5,838,160	11/17/1998	Beaman et al.			
	DM	4,571,540	2/18/1986	Stowers et al.			
	DN	4,116,523	09/26/78	Coberly et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	DO						
	DP						
	DQ						
	DR						
	DS						
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	DU						
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